

Advancing layered cathode material's cycling stability from uniform doping to non-uniform doping

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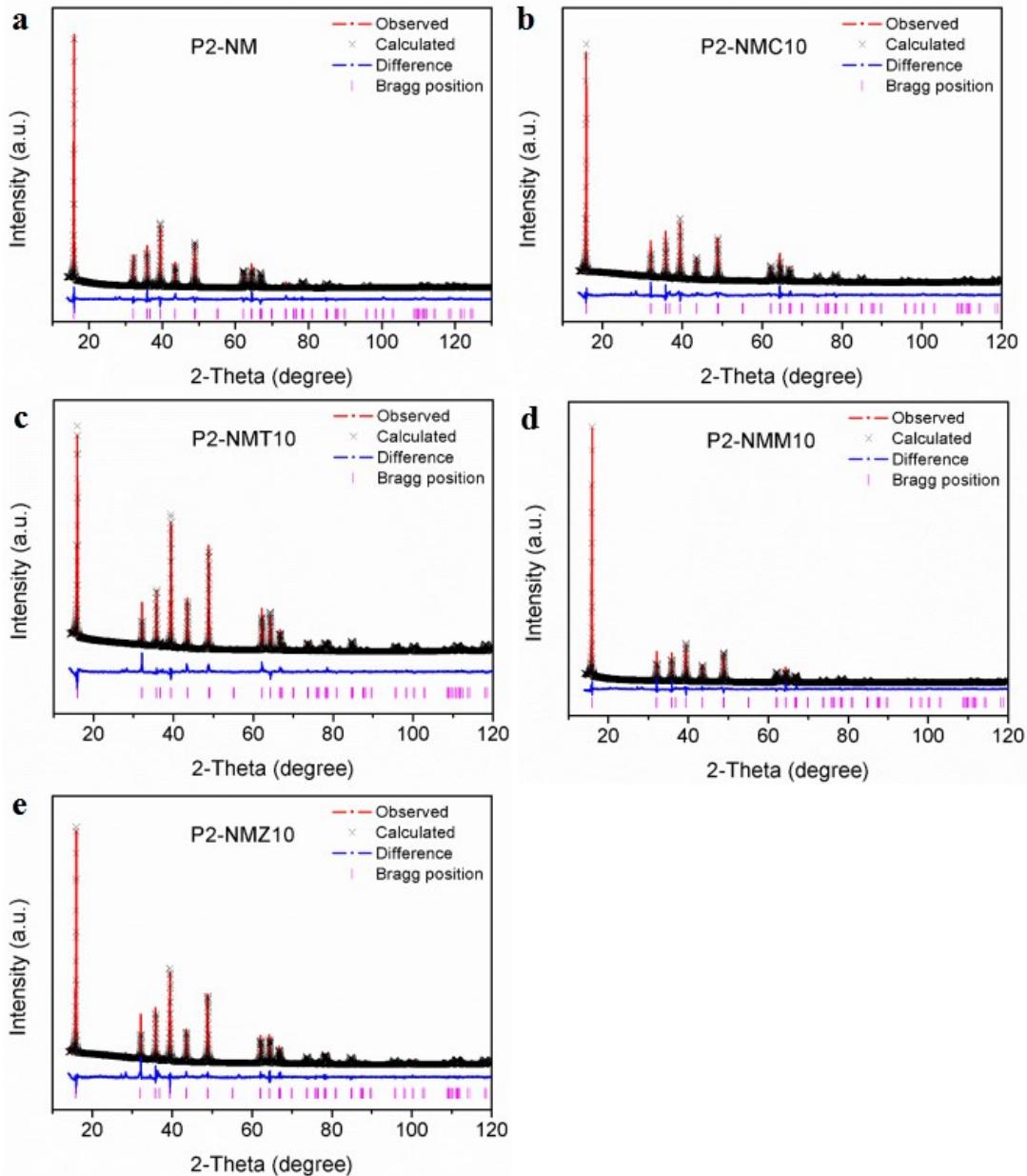


Figure S1. XRD Rietveld refinement patterns of (a) $\text{P2-Na}_{0.67}\text{Ni}_{0.33}\text{Mn}_{0.67}\text{O}_2$ (P2-NM), (b) $\text{P2-Na}_{0.67}\text{Ni}_{0.23}\text{Mn}_{0.67}\text{Cu}_{0.1}\text{O}_2$ (P2-NMC10), (c) $\text{P2-Na}_{0.67}\text{Ni}_{0.33}\text{Mn}_{0.57}\text{Ti}_{0.1}\text{O}_2$ (P2-NMT10), (d) $\text{P2-Na}_{0.67}\text{Ni}_{0.23}\text{Mn}_{0.67}\text{Mg}_{0.1}\text{O}_2$ (P2-NMM10), (e) $\text{P2-Na}_{0.67}\text{Ni}_{0.23}\text{Mn}_{0.67}\text{Zn}_{0.1}\text{O}_2$ (P2-NMZ10), which confirm that the materials are all in P2 layered structure with the $\text{P}6_3/\text{mmc}$ space group.

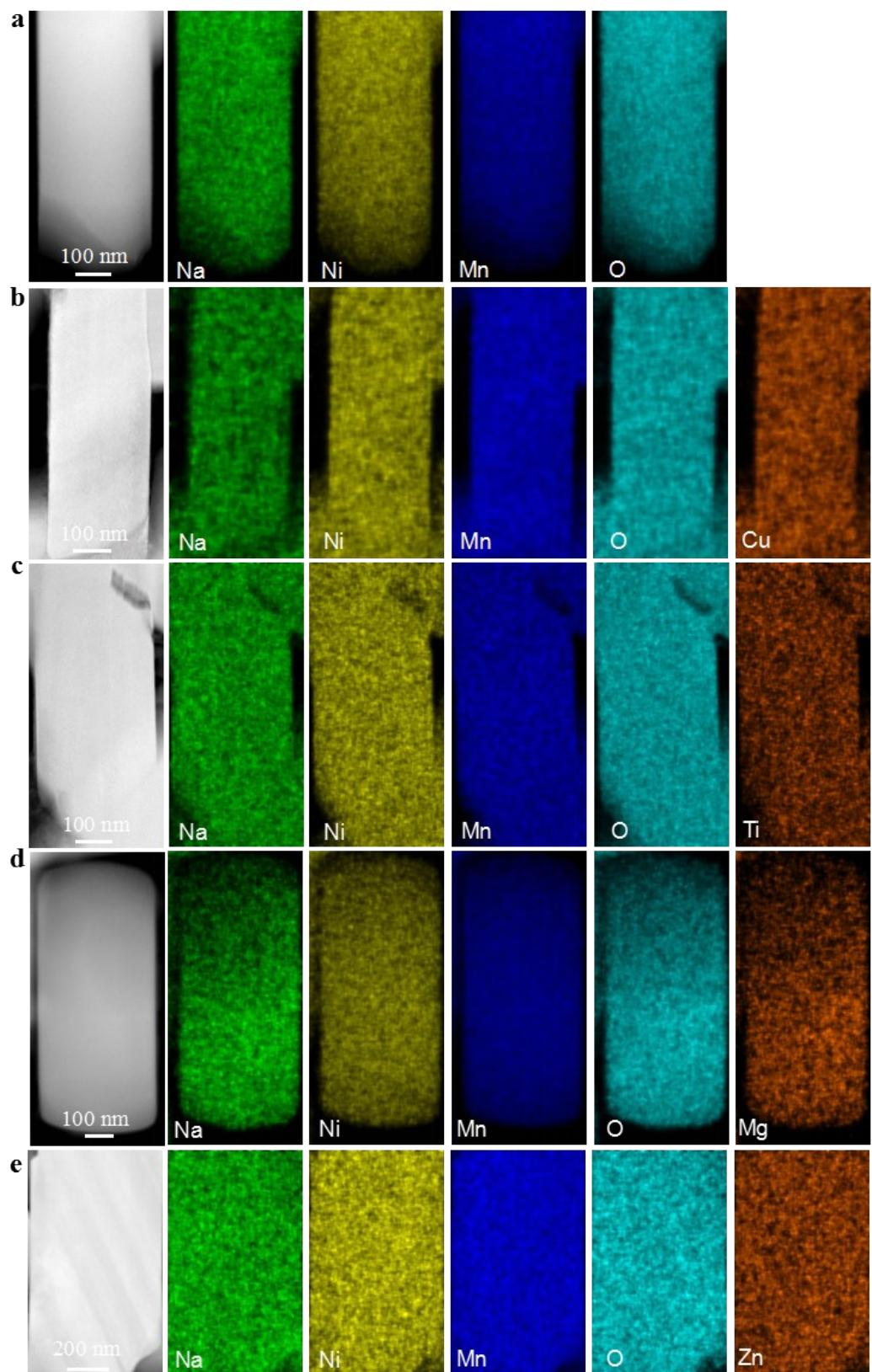


Figure S2. STEM-EDS mappings show that elements are uniformly distributed in the as-prepared samples. (a) P2-NM, (b) P2-NMC10, (c) P2-NMT10, (d) P2-NMM10 and (e) P2-NMZ10.

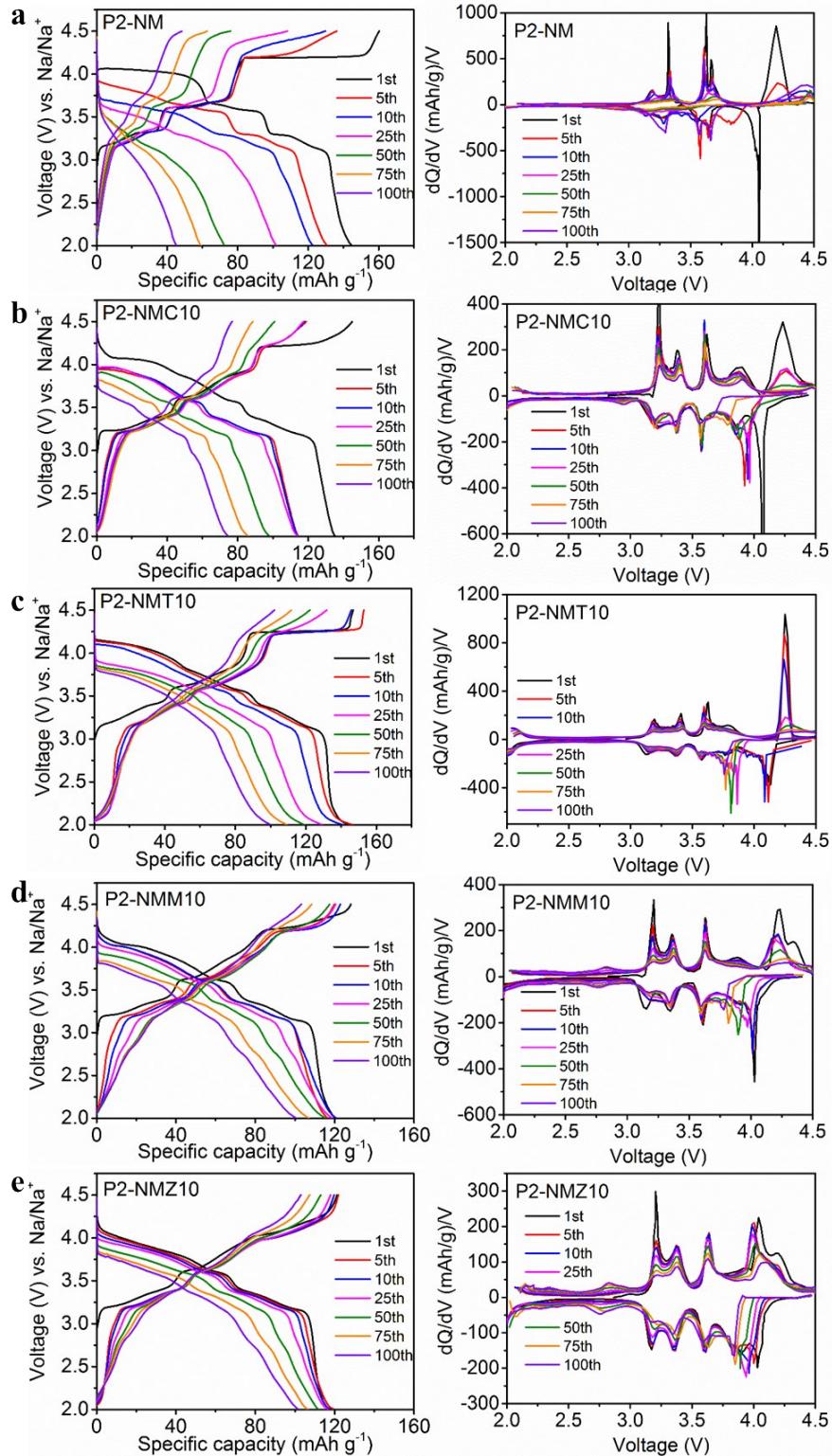


Figure S3. Charge/discharge voltage profiles and corresponding dQ/dV curves of the five cathodes cycled at 2.0–4.5 V. **(a)** P2-NM, **(b)** P2-NMC10, **(c)** P2-NMM10, **(d)** P2-NMM10 and **(e)** P2-NMZ10.

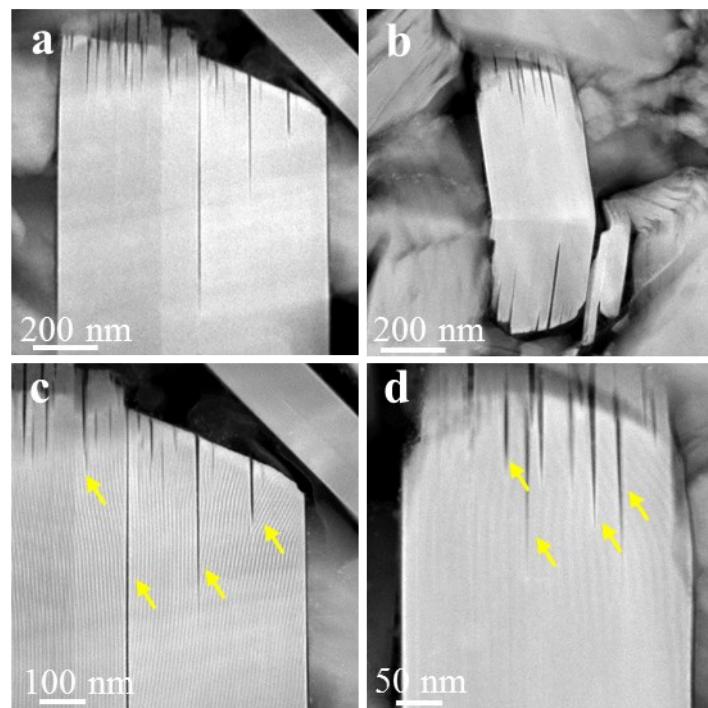


Figure S4. Low magnification cross sectional STEM-HAADF images show cracks (highlighted by yellow arrows) in the P2-NMC10 cathode after 50 cycles.

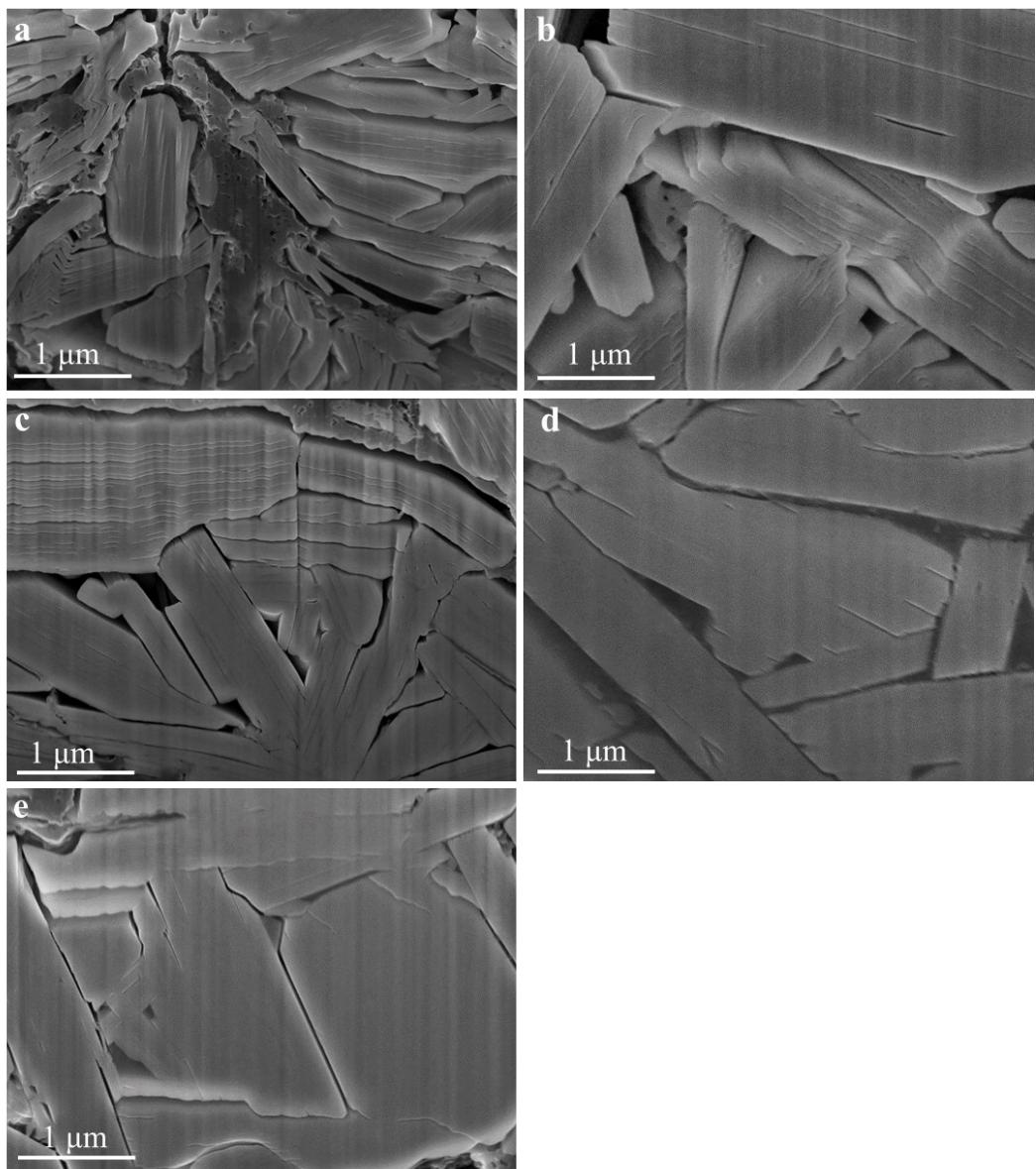


Figure S5. Cross sectional SEM images for the different cathode samples after 50 cycles at 2.0-4.5 V. (a) P2-NM sample. (b) P2-NMC10 sample. (c) P2-NMT10 sample. (d) P2-NMM10 sample. (e) P2-NMZ10 sample.

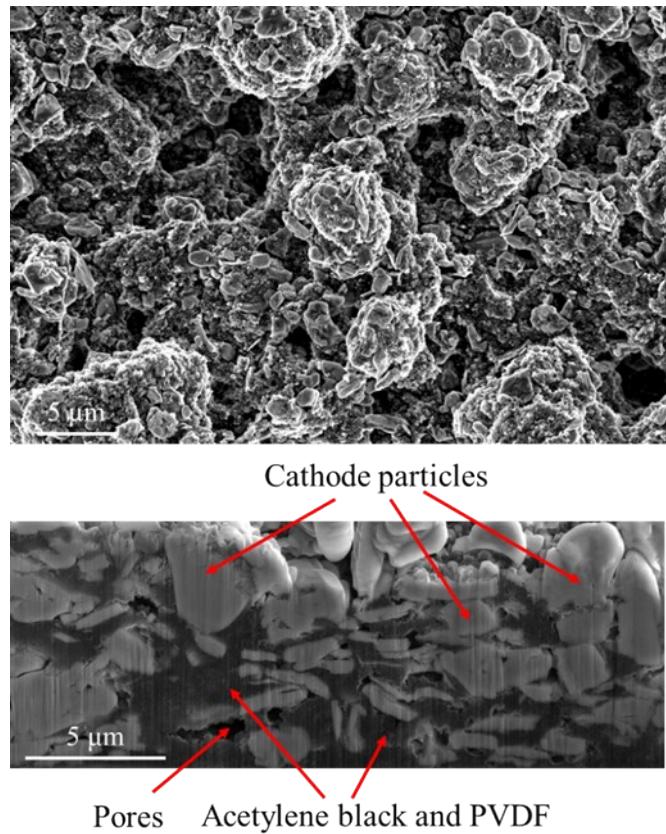


Figure S6. (a) The plan-view and (b) cross-sectional SEM image of the P2-NMZ10 cathode materials showing the distribution of pores, cathode particles, acetylene black and PVDF.

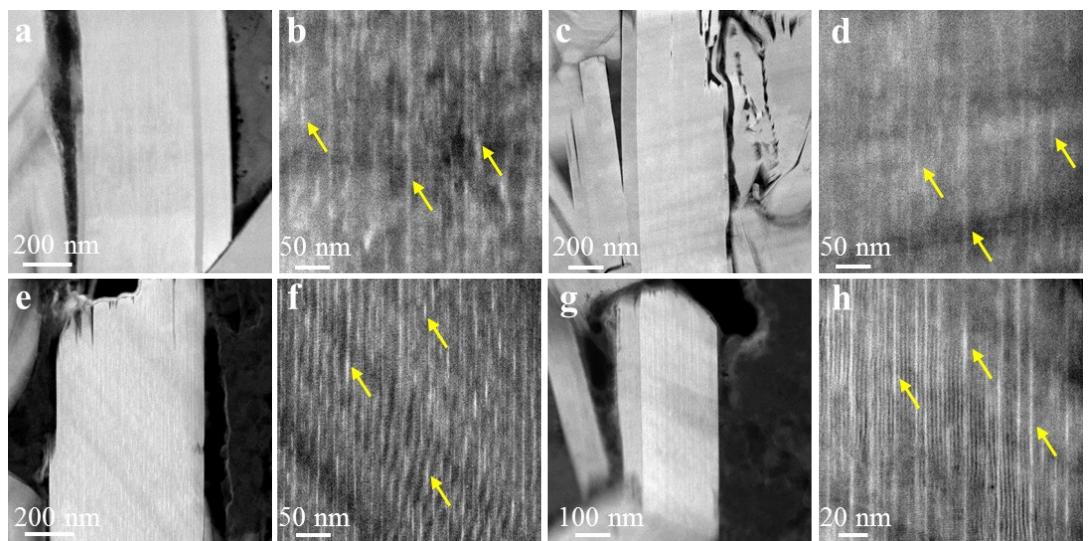


Figure S7. Observing bright stripes (highlighted by yellow arrows) in (a-d) P2-NMM10 and (e-h) P2-NMZ10 after 50 cycles at 2.0-4.5 V by STEM-HAADF.

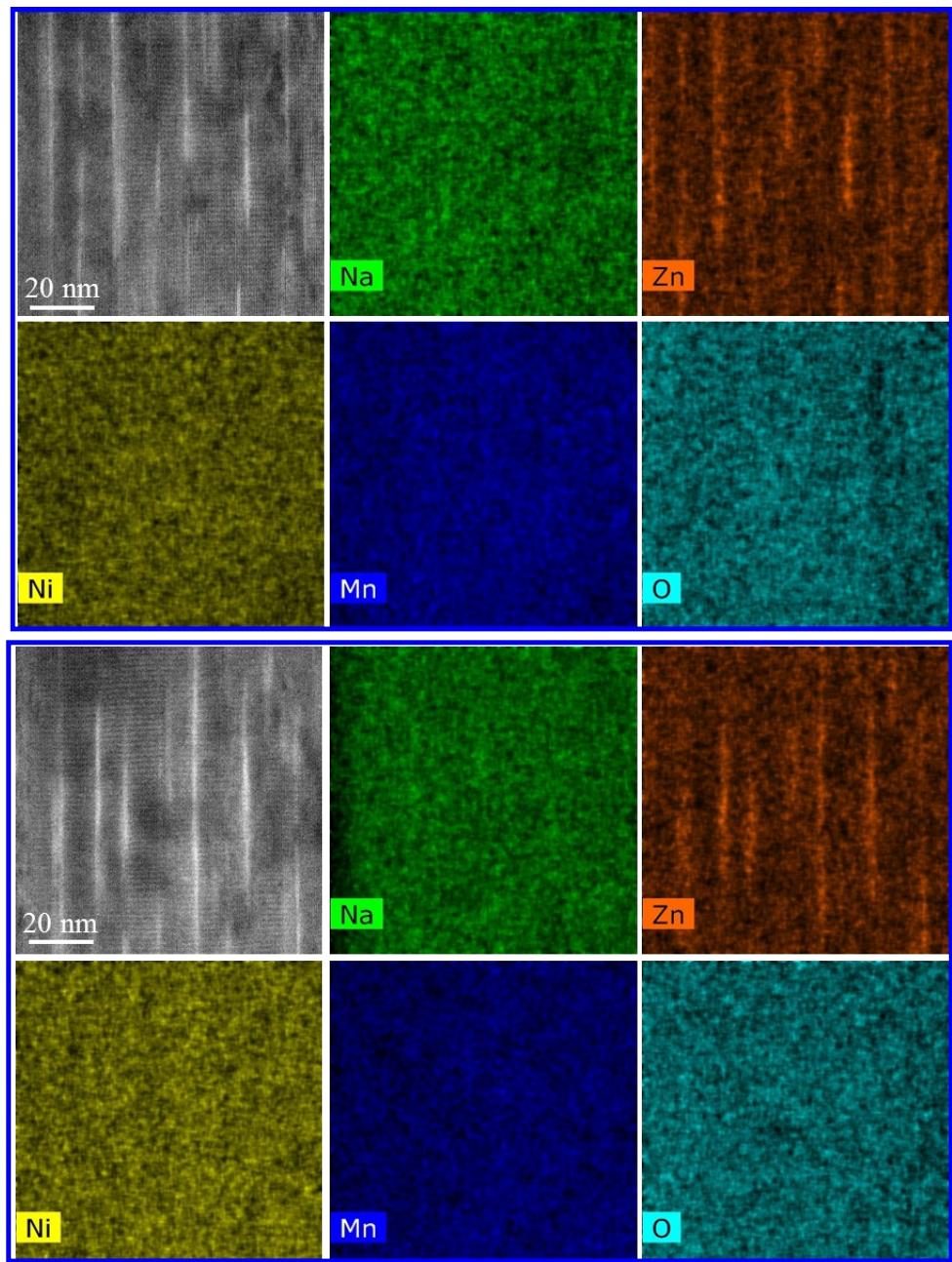


Figure S8. STEM-HAADF images and corresponding EDS of P2-NMZ10 after 50 cycles at 2.0-4.5 V, showing that only Zn element segregation in bright stripes.

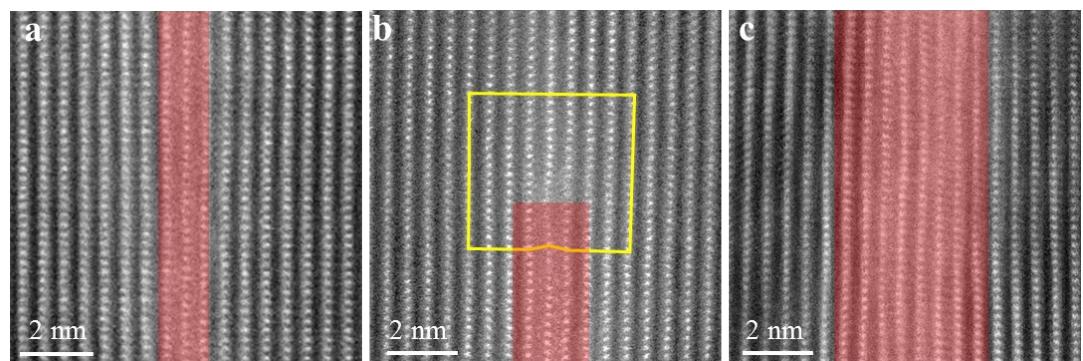


Figure S9. **a**, A two-layer thick precipitate. **b**, A multi-layer thick precipitate with one end terminated in the P2 structured matrix. The yellow circuit highlights a zigzag stacking sequence due to displacement. **c**, A multi-layer thick precipitate. The red regions highlight the lattice structure change.

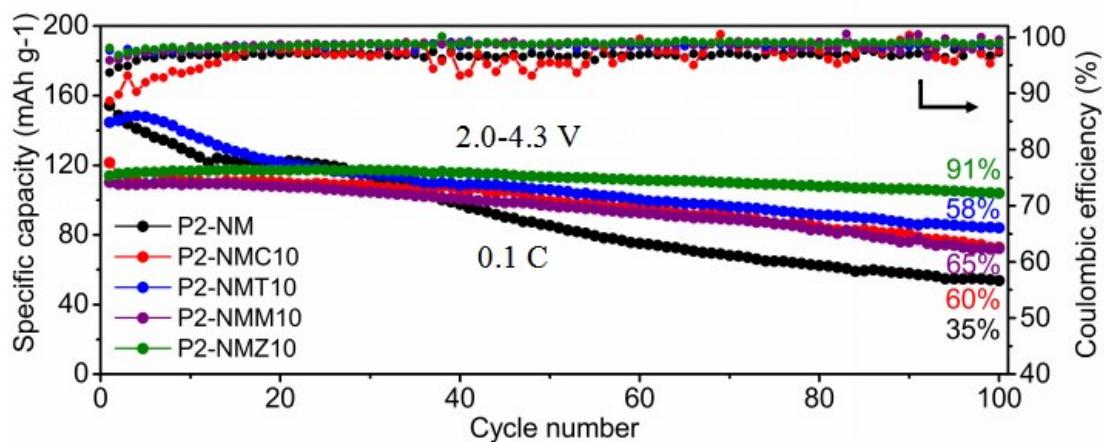


Figure S10. Electrochemical performance of the five P2-structured cathode materials (P2-NM, P2-NMC10, P2-NMT10, P2-NMM10 and P2-NMZ10) cycled at 2.0-4.3 V after 100 cycles.

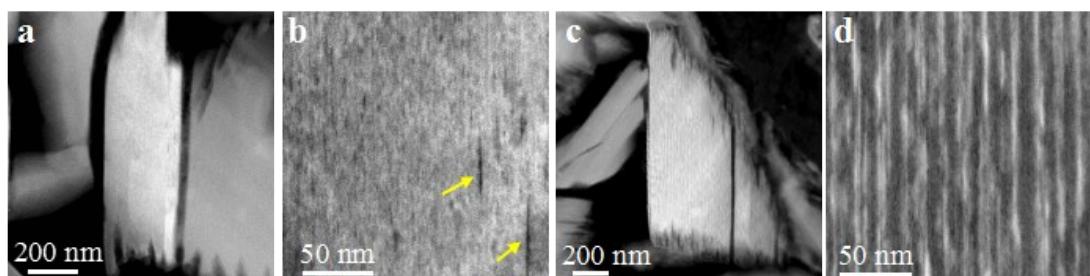


Figure S11. Cross sectional STEM-HAADF images of the **(a, b)** P2-NMM10 and **(c, d)** P2-NMZ10 cathodes cycled at 4.5 V after 200 cycles, respectively. **b**, no bright stripes, high density of dark spots and low density of cracks in P2-NMM10 cathode. Yellow arrows in **(b)** highlight the cracks in grain interior induced by high density of dark spots. **d**, high density of bright stripes, low density of dark spots and no cracks in P2-NMZ10 cathode.

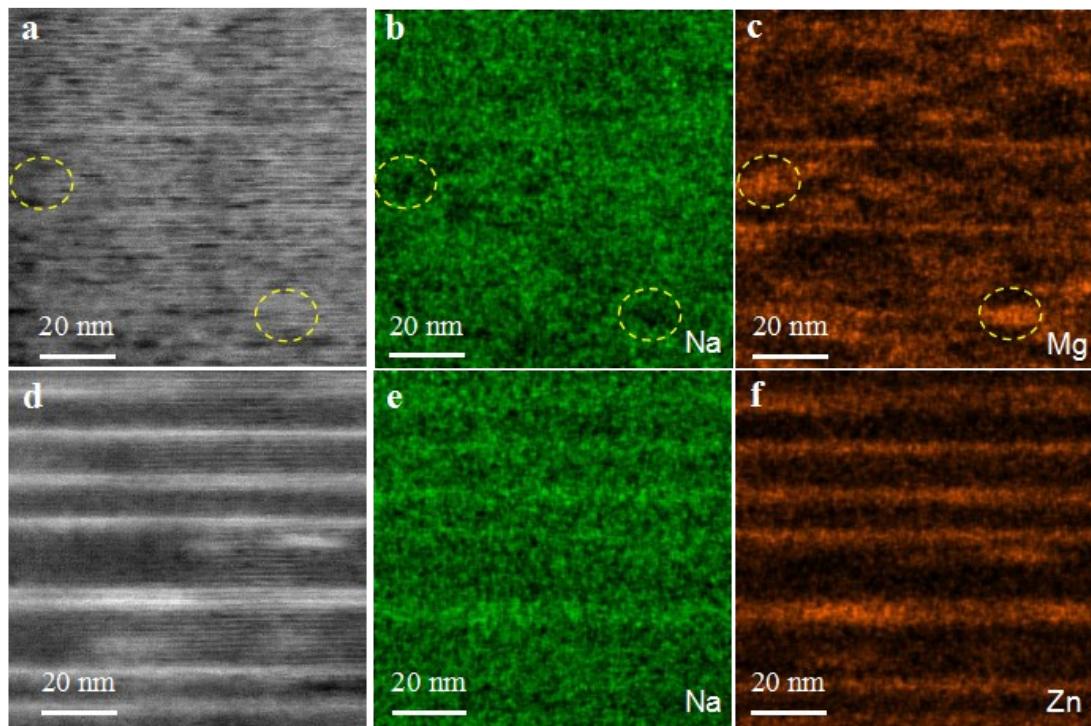


Figure S12. Cross sectional STEM-HAADF images of the (a-c) P2-NMM10 and (d-f) P2-NMZ10 cathodes cycled at 4.5 V after 200 cycles. **a**, Contrast from the precipitates become weaker and high density of dark spots appear in P2-NMM10 sample cycled at 4.5 V after 200 cycles. **(b, c)** EDS mappings show the distributions of Na and Mg are not uniform. Mg dopant segregation is evident. **d**, High density of bright stripes in P2-NMZ10 sample cycled at 4.5 V after 200 cycles. **(e, f)** The EDS mappings show the precipitates are Na-rich and Zn-rich regions.

Table S1. Crystallographic parameters of synthesized P2-Na_{0.67}Ni_{0.33}Mn_{0.67}O₂ (P2-NM) refined by the Rietveld method

Space group	P6 ₃ /mmc	No.194			
Atom	site	X	Y	Z	Occ.
Na _f	2b	0	0	0.25	0.2358
Na _e	2d	0.3333	0.6667	0.25	0.4000
Ni	2a	0	0	0	0.3333
Mn	2a	0	0	0	0.6667
O	4f	0.6667	0.3333	0.0875	1.0000
a=2.8933(4) Å	c=11.1561(9) Å	V=80.880(9) Å ³	Rp=2.74%	Rwp=4.04%	S=2.6090

Table S2. Crystallographic parameters of synthesized P2-Na_{0.67}Ni_{0.23}Mn_{0.67}Cu_{0.1}O₂ (P2-NMC10) refined by the Rietveld method.

Space group	P6 ₃ /mmc	No.194			
Atom	site	X	Y	Z	Occ.
Na _f	2b	0	0	0.25	0.2139
Na _e	2d	0.3333	0.6667	0.25	0.4506
Ni	2a	0	0	0	0.2235
Mn	2a	0	0	0	0.6624
Cu	2a	0	0	0	0.1
O	4f	0.6667	0.3333	0.07682	1.0000
a=2.8938(9) Å	c=11.1675(1) Å	V=80.993(7) Å ³	Rp=2.782%	Rwp=4.05%	S=2.6380

Table S3. Crystallographic parameters of synthesized P2-Na_{0.67}Ni_{0.33}Mn_{0.57}Ti_{0.1}O₂ (P2-NMT10) refined by the Rietveld method.

Space group	P6 ₃ /mmc	No.194			
Atom	site	X	Y	Z	Occ.
Na _f	2b	0	0	0.25	0.2157
Na _e	2d	0.3333	0.6667	0.25	0.4521
Ni	2a	0	0	0	0.3222
Mn	2a	0	0	0	0.5597
Ti	2a	0	0	0	0.1
O	4f	0.6667	0.3333	0.07992	1.0000
a=2.9002(5) Å	c=11.1210(0) Å	V=81.229(9) Å ³	Rp=2.069%	Rwp=3.33%	S=2.1560

Table S4. Crystallographic parameters of synthesized P2-Na_{0.67}Ni_{0.23}Mn_{0.67}Mg_{0.1}O₂ (P2-NMM10) refined by the Rietveld method.

Space group	P6 ₃ /mmc		No.194			
Atom	site		X	Y	Z	Occ.
Na _f	2b		0	0	0.25	0.2139
Na _e	2d		0.3333	0.6667	0.25	0.4561
Ni	2a		0	0	0	0.2316
Mn	2a		0	0	0	0.6684
Mg	2a		0	0	0	0.1
O	4f		0.6667	0.3333	0.07992	1.0000
a=2.8943(9) Å	c=11.1708(6) Å	V=81.046(2) Å ³	Rp=3.256%	Rwp=4.77%	S=2.4339	

Table S5. Crystallographic parameters of synthesized P2-Na_{0.67}Ni_{0.23}Mn_{0.67}Zn_{0.1}O₂ (P2-NMZ10) refined by the Rietveld method.

Space group	P6 ₃ /mmc		No.194			
Atom	site		X	Y	Z	Occ.
Na _f	2b		0	0	0.25	0.2169
Na _e	2d		0.3333	0.6667	0.25	0.4516
Ni	2a		0	0	0	0.2214
Mn	2a		0	0	0	0.6632
Zn	2a		0	0	0	0.1
O	4f		0.6667	0.3333	0.09089	1.0000
a=2.8987(9) Å	c=11.1750(9) Å	V=81.323(4) Å ³	Rp=2.934%	Rwp=4.403%	S=2.6382	